

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/797,260	WENG ET AL.	
Examiner	Art Unit	
Caridad M. Everhart	2891	

SEARCHED					
Class	Subclass	Date	Examiner		
438	29	4/6/2005	СМЕ		
		-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST(attached)	4/6/2005	CME		
EAST:(mim and (led or oled or (electro adj optical)) and anodiz\$6)	4/6/2005	СМЕ		